## Notice of References Cited

Application/Control No.	A = = line = t/a \/Data	mt I I and a se	
Application/Control No.	Applicant(s)/Pate	nt Under	
09/616,076	Reexamination ISHIBASHI ET AL.		
Examiner	Art Unit		
Sharon E. Pavne	2881	Page 1 of 1	

## U.S. PATENT DOCUMENTS

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classif	Classification	
	Α	US-5,936,237	08-1999	Van der Weide	250	234	
	В	US-6,079,255	06-2000	Binnig et al.	73	105	
	Ċ	US-5,245,187	09-1993	Kawase et al.	250	306	
	D	US-5,360,978	11-1994	Gueret	250	306	
	Е	US-5,537,863	07-1996	Fujiu et al.	73	105	
	F	ÚS-6,014,032	01-2000	Maddix et al.	324	762	
	G	US-5,886,922	03-1999	Saito et al.	365	164	
	Н	US-6,232,143 B1	05-2001	Maddix et al.	438	100	
	1	US-6,088,320	07-2000	Bayer et al.	369	101	
	J	US-					
	K	US-					
	L	US-					
	М	US-					

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
ī	Р					
	Q					
	R					
	S					
	Т				Alternative Access	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	.w				
	x				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.